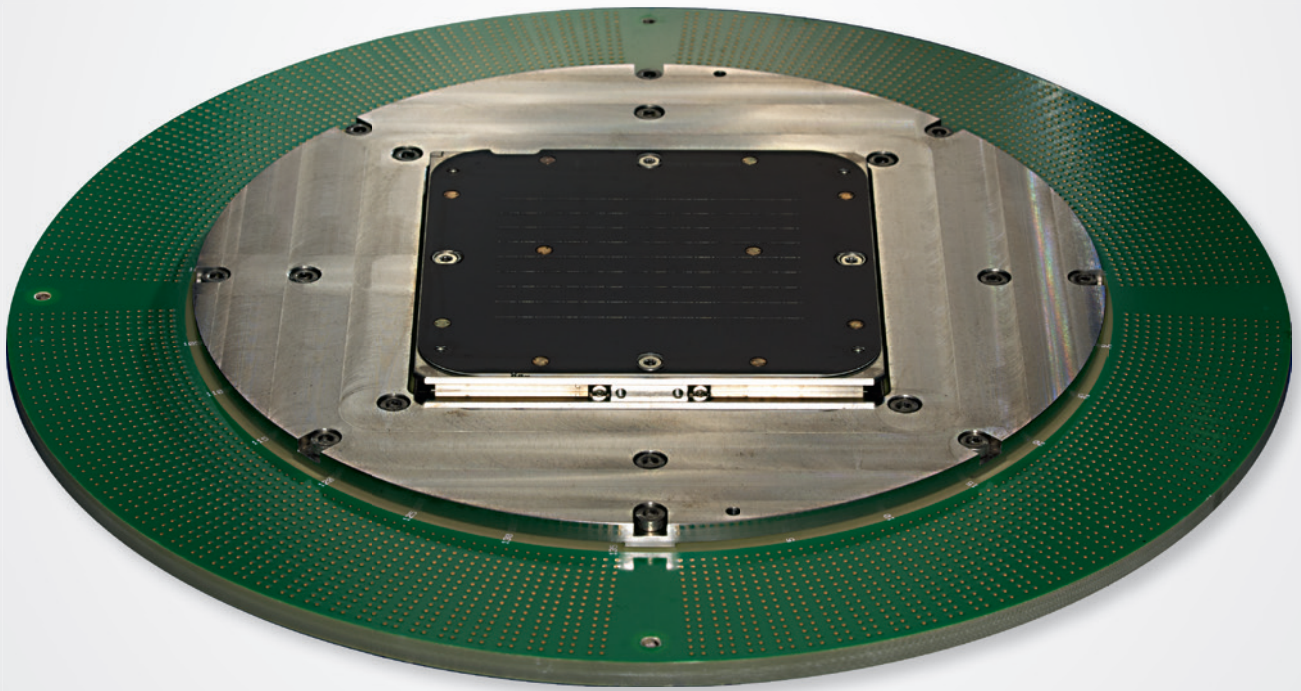


# Direct Attach ViProbe® Series

Probe Cards for Wafer Test



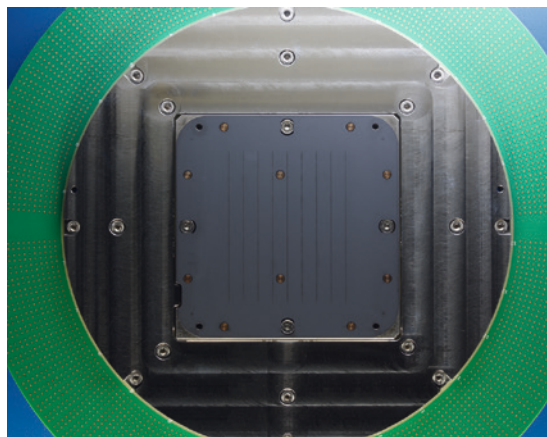
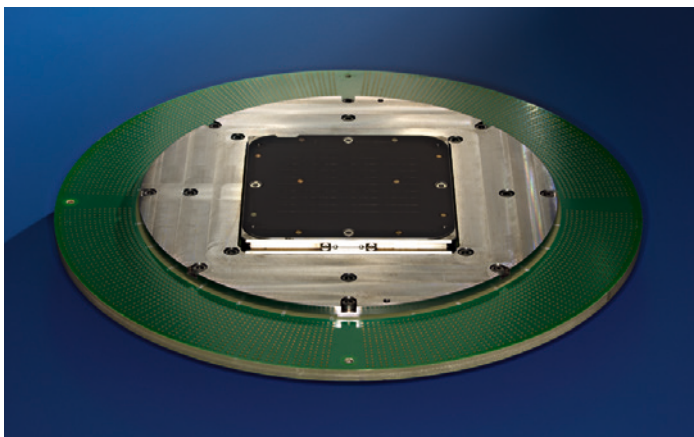
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## Direct Attach ViProbe® Series

FEINMETALL Direct Attach ViProbe® Series represents a technology in advanced wafer probing. Our Direct Attach ViProbe® Series is designed for high performance and high pin count probe cards.

These products provide the capability for substantial time- and cost- savings in wafer testing.



### 7 good reasons for using Direct Attach ViProbe® Series – the Vertical Probe Card Technology from FEINMETALL

- Excellent electrical performance
- Full wafer test possible
- Easy Maintenance & Service
- Easy exchange of needles
- Precise alignment over the entire lifetime
- Tolerates changing planarity conditions
- Made in Germany

### Key Parameters D09 / D32 / D41 / D42

<b>Active Area:</b>	from 17x17mm (D41) to 80x80mm (D09) or Ø 213 mm (D32)
<b>Tester:</b>	Teradyne J750, µFlex Advantest V93000 all other testers possible
<b>Pitch:</b>	min 72µm
<b>Test Points:</b>	up to 10.000
<b>Temperature:</b>	-40°C...+180°C

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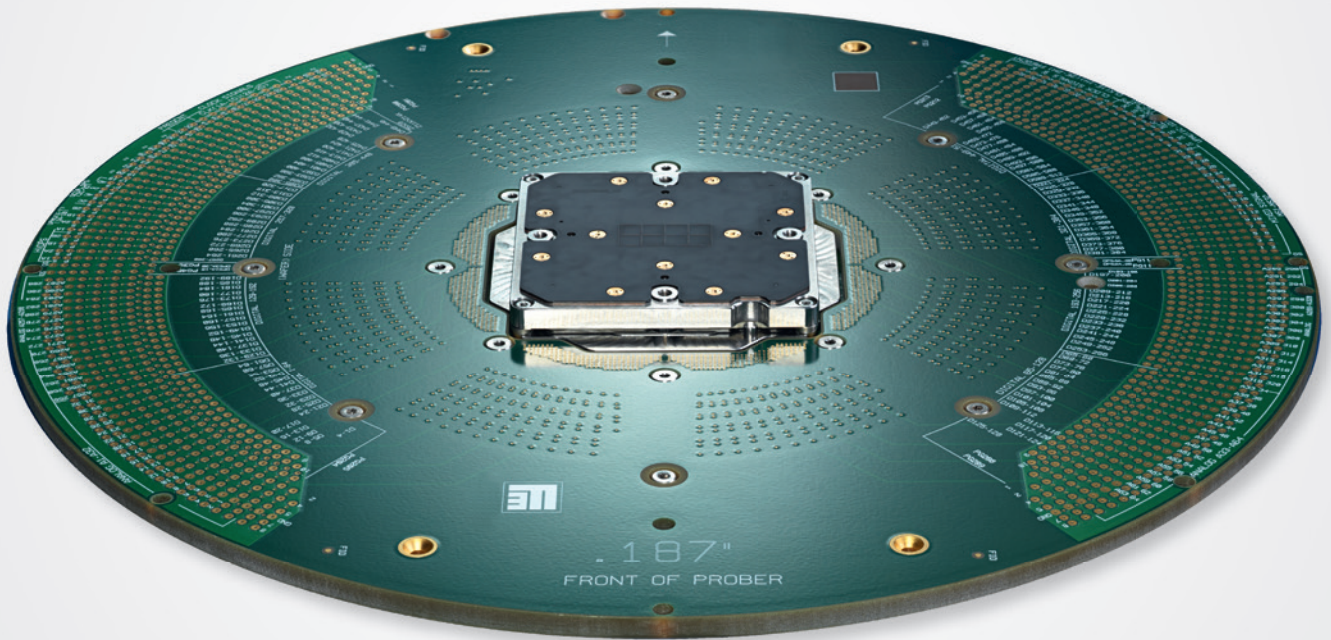
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# ViProbe® Space Transformer Series

Probe Cards for Wafer Test



**50**  
**YEARS**  
Good Contacts

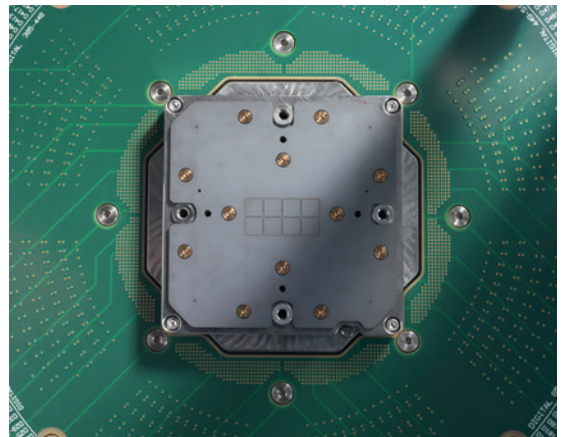
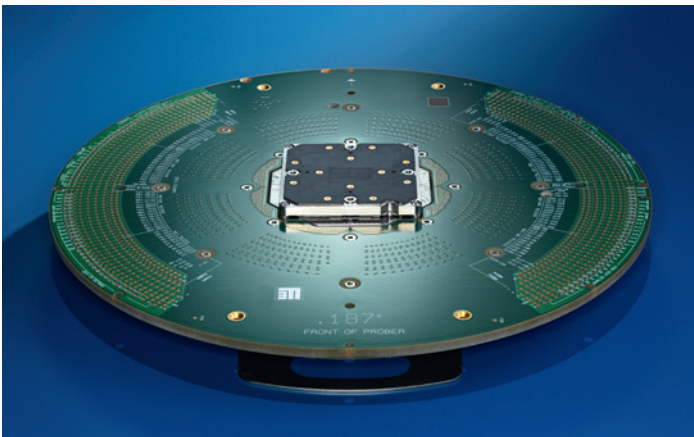
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## ViProbe® Space Transformer Series

FEINMETALL ViProbe® Space Transformer Series represents a leading technology in advanced wafer probing. The advantages of our ViProbe® Space Transformer Series are excellent electrical performance, high pin count-, high parallel testing as well as excellent temperature behaviour.

ViProbe® Space Transformer Series products are based on MLC and MLO Technology. These products provide the capability for substantial time- and cost- savings in wafer testing.



### 7 good reasons for using ViProbe® Space Transformer Series the Vertical Probe Card Technology from FEINMETALL

- Excellent electrical performance
- Easy Maintenance & Service
- Easy exchange of needles
- Precise alignment over the entire lifetime
- Excellent temperature behaviour
- Minimum impact on the bond pad
- Tolerates changing planarity conditions

#### Key Parameters

**M22 / M23 / S22 / S23 / S24**

<b>Active Area:</b>	40x40mm (M22/M23/ S22/S23) 50x80mm (S24)
<b>Tester:</b>	Teradyne J750, µFlex Advantest V93000 other testers on request
<b>Pitch:</b>	min 56µm
<b>Test Points:</b>	up to 10 000
<b>Temperature:</b>	-40°C...+180°C

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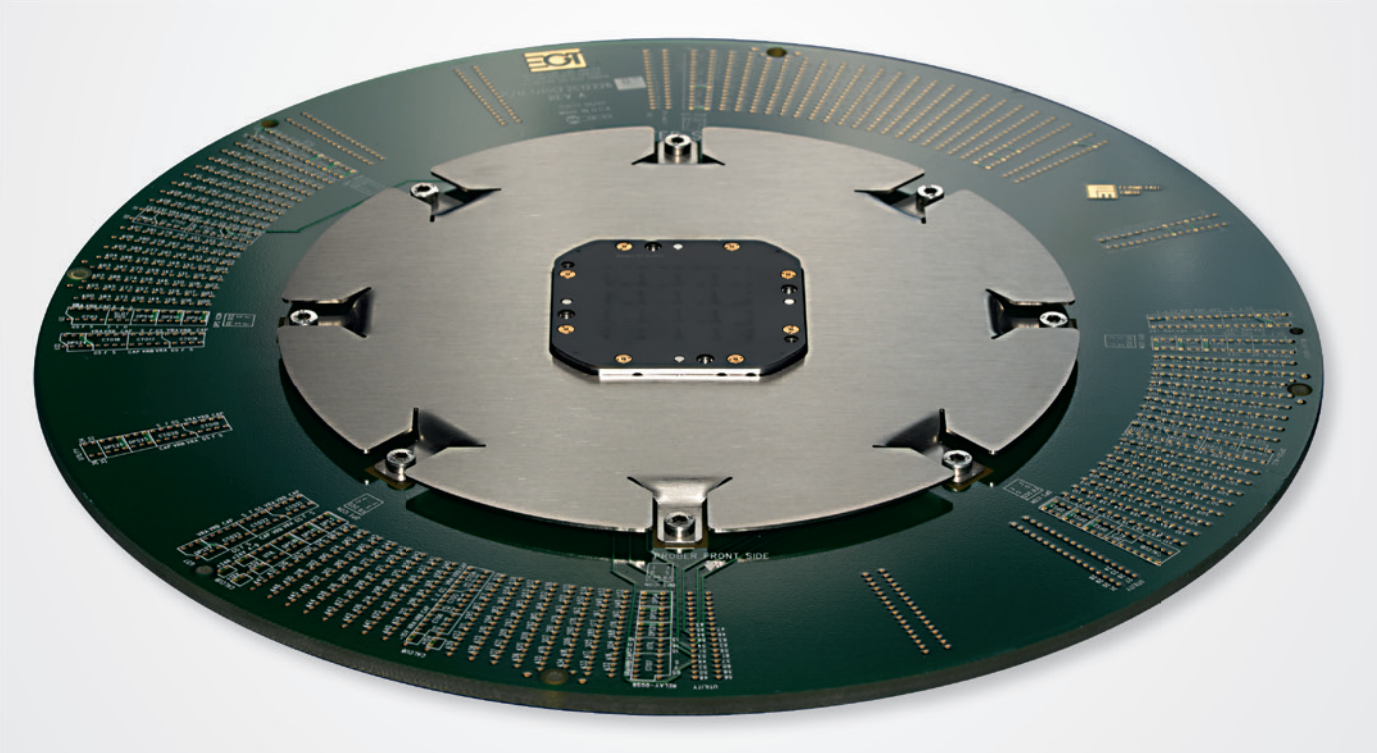
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**FEINMETALL**  
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# ViProbe® Wired Series

Probe Cards for Wafer Test



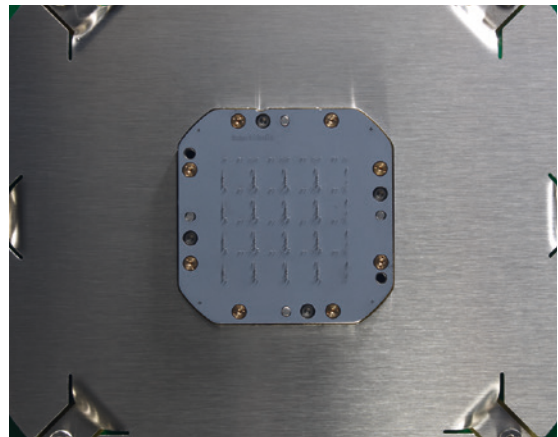
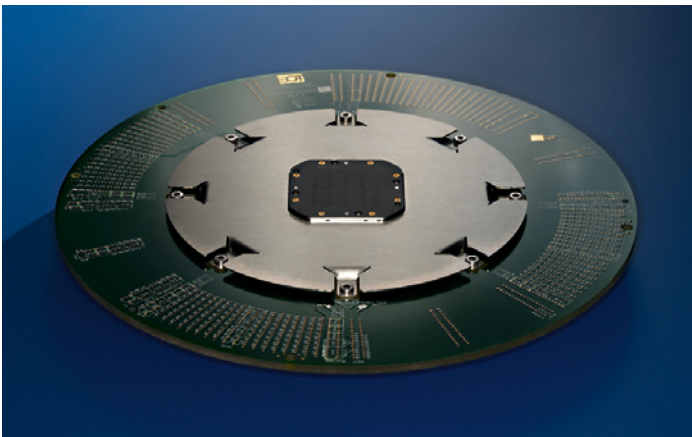
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## ViProbe® Wired Series

FEINMETALL ViProbe® Wired Series represents a technology in advanced wafer probing. The advantages of our ViProbe® Wired Series are fast lead time, high flexibility as well as flexible probe tip depth.

ViProbe® Wired Series products are based on Wired Version Technology. These products provide the capability for substantial time- and cost- savings in wafer testing.



### 7 good reasons for using ViProbe® Wired Series the Vertical Probe Card Technology from Feinmetall

- Fast lead time and flexibility
- Easy Maintenance & Service
- Easy exchange of needles
- Precise alignment over the entire lifetime
- Excellent temperature behaviour
- Minimum impact on the bond pad
- Tolerates changing planarity conditions

#### Key Parameters

W10 / W40 / W41 / W42 / W43

<b>Active Area:</b>	from 9 x 10 mm (W40) to 45x45mm (W43)
<b>Tester:</b>	Teradyne J750, µFlex Advantest V93000 all other testers possible
<b>Pitch:</b>	min 56µm
<b>Test Points:</b>	up to 3.500
<b>Temperature:</b>	-40°C...+180°C

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